Searched



Application/Control No.

Applicant(s)/Patent Under Reexamination

KAKIZAKI ET AL.

Examiner

10058781

Kim, David S

Art Unit

2633 **2**613

	i
03/30/2006	DSK, 9/15/06, 10/3/06
09/15/2006	DSK, 9/29/06
09/29/2006	DSK
	09/15/2006

Search Notes



Application/Control No.

Applicant(s)/Patent Under Reexamination

10058781

KAKIZAKI ET AL.

Examiner

Kim, David S

Art Unit

2033 2613

Notes	Date	Examiner
EAST search - see search history printout	03/30/2006	DSK, 3/31/06, 4/3/06
www.google.com - various combinations of the following terms: monitor detect optical switch reflections	04/03/2006	DSK
scholar.google.com - various combinations of the following terms: monitor detect optical switch reflections	04/03/2006	DSK
ieeexplore.ieee.org - various combinations of the following terms: optic* photon* switch monitor* locat* detect* reflect* deflect*	04/03/2006	DSK
text search in 359/196-226	04/03/2006	DSK
consulted with Examiner Mohammad Sedighian allowability of claim 11	04/03/2006	DSK .
consulted with SPE Jason Chan about the allowability of claims 5-6	04/03/2006	DSK
EAST search - see search history printout	09/15/2006	DSK, 9/27 - 9/29/06, 10/3 - 10/4/06
Interference search on EAST - see search history printout	09/27/2006	DSK, 9/28/06
reviewed references in U.S. Patent Application Nos. 10/040,226	10/03/2006	DSK
text search in 370/244	10/3/2006	DSK
ieeexplore.ieee.org - search terms: (fault <sentence> locat*) and (reflect* or deflect*) and (switch* or cross-connect* or (cross <near 1=""> connect*) or router or routing)</near></sentence>	10/04/2006	DSK
scholar.google.com - various combinations of the following terms: fault location reflect deflect switch cross-connect cross connect router routing optical	10/04/2006	DSK, 10/5/06
www.google.com - various combinations of the following terms: fault location reflect deflect switch cross-connect cross connect router routing optical	10/05/2006	DSK .
U.S. Patent and Trademark Office		Part of Paper No.: 20061017

Interference Searched



Application/Control No.

Applicant(s)/Patent Under Reexamination

KAKIZAKI ET AL.

Examiner

10058781

Kim, David S

Art Unit

2633- 2613

Class	SubClass	Date		Examiner
Interference search on EAST		09/27/2006	DSK, 9/28/06	
U.S. Patent and Trademark Office	· · · · · · · · · · · · · · · · · · ·		Part of Paper No.:	20061017